

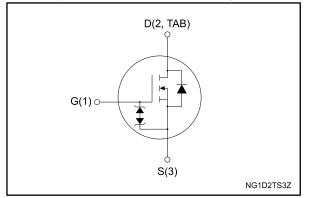
# STP35N60DM2

Datasheet - production data

### N-channel 600 V, 0.094 Ω typ., 28 A MDmesh<sup>™</sup> DM2 Power MOSFET in a TO-220 package

TAB TAB TO-220

Figure 1: Internal schematic diagram



### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ID	Ртот
STP35N60DM2	600 V	0.110 Ω	28 A	210 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

### **Applications**

• Switching applications

### Description

This high voltage N-channel Power MOSFET is part of the MDmesh<sup>TM</sup> DM2 fast recovery diode series. It offers very low recovery charge ( $Q_{rr}$ ) and time ( $t_{rr}$ ) combined with low  $R_{DS(on)}$ , rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

#### Table 1: Device summary

Order code	Marking	Package	Packing
STP35N60DM2	35N60DM2	TO-220	Tube

1/13

This is information on a product in full production.

### Contents

### Contents

1	Electric	al ratings	3
2	Electric	al characteristics	4
	2.1	Electrical characteristics (curves)	6
3	Test cir	cuits	8
4	Packag	e information	9
	4.1	TO-220 type A package information	10
5	Revisio	on history	



## 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>GS</sub>	Gate-source voltage	±25	V
	Drain current (continuous) at T <sub>case</sub> = 25 °C	28	٨
Ι <sub>D</sub>	Drain current (continuous) at T <sub>case</sub> = 100 °C	17	A
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	112	А
P <sub>TOT</sub>	Total dissipation at T <sub>case</sub> = 25 °C	210	W
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	50	V/ns
dv/dt <sup>(3)</sup>	MOSFET dv/dt ruggedness	50	v/ns
T <sub>stg</sub>	Storage temperature	-55 to 150	°C
Tj	Operating junction temperature	-55 10 150	C

#### Notes:

 $^{\left( 1\right) }$  Pulse width is limited by safe operating area.

 $^{(2)}$  I\_{SD}  $\leq 28$  A, di/dt=900 A/µs; V\_{DS} peak < V\_{(BR)DSS}, V\_{DD} = 400.

<sup>(3)</sup>  $V_{DS} \le 480 \text{ V}.$ 

#### Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	0.6	9 <b>0</b> A A /
R <sub>thj-amb</sub>	Thermal resistance junction-amb	62.5	°C/W

#### Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not repetitive	6	А
E <sub>AS</sub> <sup>(1)</sup>	Single pulse avalanche energy	650	mJ

#### Notes:

 $^{(1)}$  starting  $T_{j}$  = 25 °C,  $I_{D}$  =  $I_{AR},\,V_{DD}$  = 50 V.



## 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$V_{GS}$ = 0 V, $I_D$ = 1 mA	600			V
	Zoro goto voltago droin	$V_{GS} = 0 V, V_{DS} = 600 V$			10	
I <sub>DSS</sub>	Zero gate voltage drain current	$V_{GS} = 0 V$ , $V_{DS} = 600 V$ , $T_{case} = 125 $ °C			100	μA
I <sub>GSS</sub>	Gate-body leakage current	$V_{DS} = 0 V, V_{GS} = \pm 25 V$			±5	μA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS}$ = $V_{GS}$ , $I_D$ = 250 $\mu$ A	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, I_D = 14 \text{ A}$		0.094	0.11	Ω

Table 6: Dynamic						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	2400	-	
C <sub>oss</sub>	Output capacitance	$V_{\text{DS}} = 100 \text{ V}, \text{ f} = 1 \text{ MHz}, \text{ V}_{\text{GS}} = 0 \text{ V}$	-	110	-	pF
Crss	Reverse transfer capacitance		-	2.8	-	
Coss eq. <sup>(1)</sup>	Equivalent output capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$ V	-	190	-	pF
R <sub>G</sub>	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	4.3	-	Ω
Qg	Total gate charge		-	54	-	
Q <sub>gs</sub>	Gate-source charge	$V_{DD}$ = 480 V, $I_D$ = 28 A, $V_{GS}$ = 10 V (see Figure 15: "Test circuit for gate charge behavior")	-	14.6	-	nC
Q <sub>gd</sub>	Gate-drain charge		-	24.2	-	

#### Notes:

 $^{(1)}$   $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .



#### Electrical characteristics

_	Table 7: Switching times							
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit		
t <sub>d(on)</sub>	Turn-on delay time	$V_{\rm ex} = 300 V_{\rm ex} = 14.0 P_{\rm e} = 4.7 O_{\rm ex}$	-	21.2	-			
tr	Rise time	$V_{DD} = 300 \text{ V}, I_D = 14 \text{ A } R_G = 4.7 \Omega,$ $V_{GS} = 10 \text{ V}$ (see <i>Figure 14: "Test circuit for</i>	-	17	-			
t <sub>d(off)</sub>	Turn-off delay time	resistive load switching times" and Figure 19: "Switching time waveform")	-	68	-	ns		
t <sub>f</sub>	Fall time		-	10.7	-			

Table 8	3: S	ource-	drain	diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		28	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		112	A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{SD} = 28 \text{ A}$	-		1.6	V
t <sub>rr</sub>	Reverse recovery time		-	120		ns
Q <sub>rr</sub>	Reverse recovery charge	$I_{SD} = 28 \text{ A}$ , di/dt = 100 A/µs, V <sub>DD</sub> = 60 V (see Figure 16: "Test circuit for inductive load switching and diode recovery times")	-	572		nC
I <sub>RRM</sub>	Reverse recovery current		-	10.2		A
t <sub>rr</sub>	Reverse recovery time		-	215		ns
Q <sub>rr</sub>	Reverse recovery charge	$I_{SD} = 28 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, V_{DD} = 60 \text{ V},$ $T_j = 150 \text{ °C}$ (see Figure 16: "Test circuit for inductive load switching and diode	-	1.89		μC
I <sub>RRM</sub>	Reverse recovery current	recovery times")	-	17.7		А

#### Notes:

<sup>(1)</sup> Pulse width is limited by safe operating area.

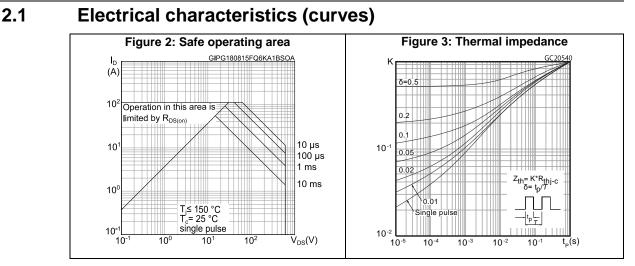
 $^{(2)}$  Pulse test: pulse duration = 300  $\mu s,$  duty cycle 1.5%.

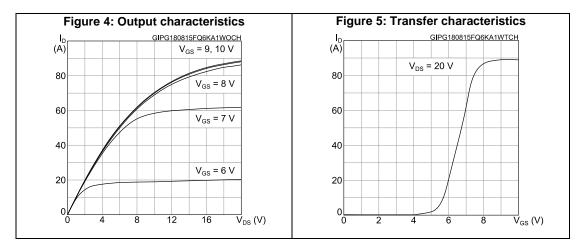
Table 9: Gate-source Zene	diode
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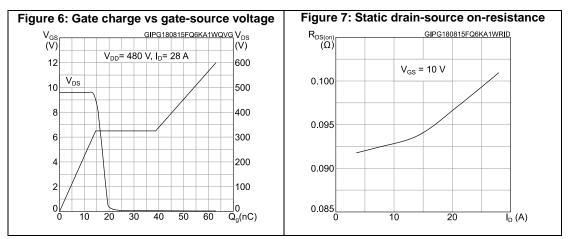
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)GSO</sub>	Gate-source breakdown voltage	$I_{GS} = \pm 250 \ \mu A, I_D = 0 \ A$	±30	-	-	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.



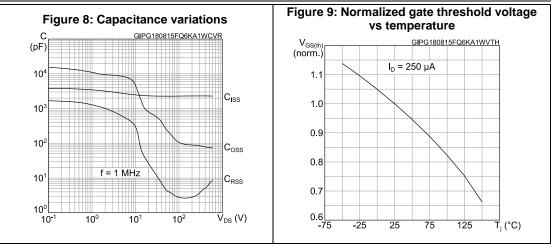


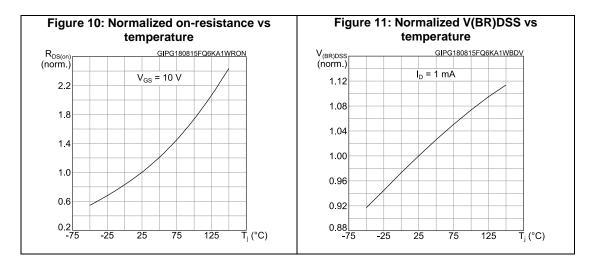


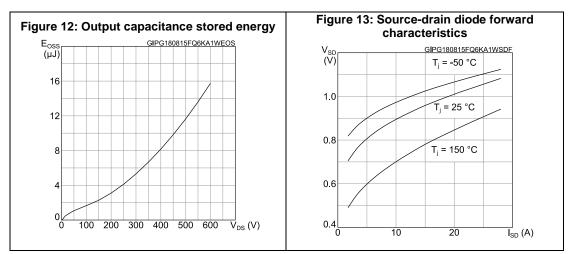




#### **Electrical characteristics**



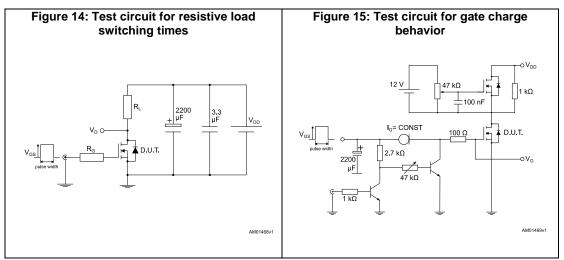


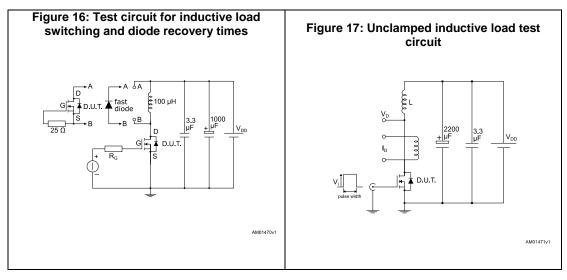


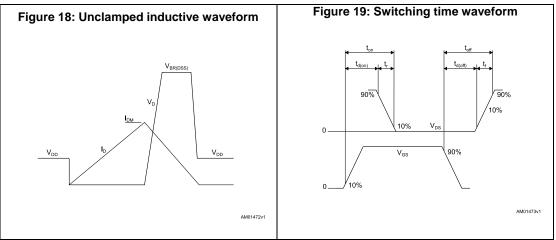
57

DocID028348 Rev 1

### 3 Test circuits







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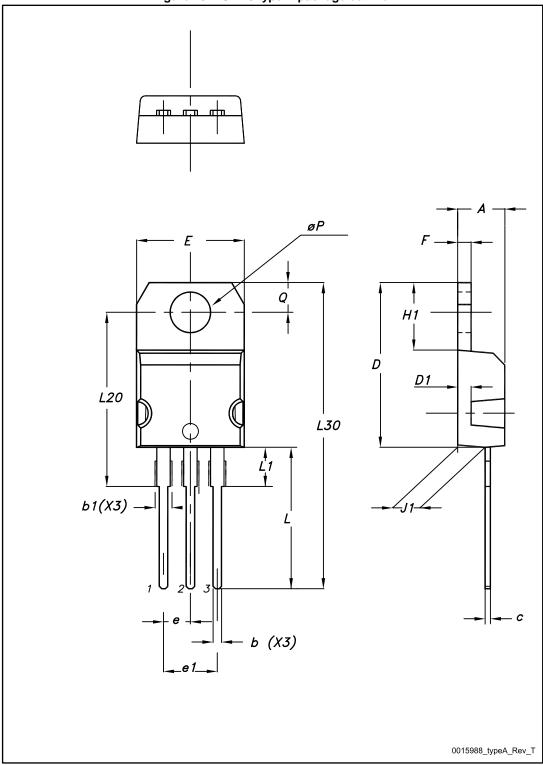


### 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK<sup>®</sup> is an ST trademark.









DocID028348 Rev 1

#### STP35N60DM2

#### Package information

			Package Information					
Table 10: TO-220 type A mechanical data								
Dim.	mm							
Dim.	Min.	Тур.	Max.					
А	4.40		4.60					
b	0.61		0.88					
b1	1.14		1.70					
С	0.48		0.70					
D	15.25		15.75					
D1		1.27						
E	10		10.40					
е	2.40		2.70					
e1	4.95		5.15					
F	1.23		1.32					
H1	6.20		6.60					
J1	2.40		2.72					
L	13		14					
L1	3.50		3.93					
L20		16.40						
L30		28.90						
øP	3.75		3.85					
Q	2.65		2.95					



## 5 Revision history

Table 11: Document revision history

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Date	Revision	Changes
10-Sep-2015	1	Initial version



#### STP35N60DM2

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